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Application/Control No.	Applicant(s)/Patent under Reexamination
10/630,643	YEW ET AL.
Examiner	Art Unit
Leonardo Andújar	2826

SEARCHED					
Class	Subclass	Date	Examiner		
257	642,643 752,758 759-765 774	6/22/2005	LA		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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(INCLUDING SEARCH	DATE	
<del></del>	DATE	EXMR
EAST search; search notes: 09/849391 & 09/203035	6/22/2005	LA
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